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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/809,720	RUGG ET AL.	
Examiner	Art Unit	
Thinh T. Nguyen	2818	

SEARCHED			
Class	Subclass	Date	Examiner
257	782	2/23/2004	TTN
257	686	2/23/2006	TTN
257	687	2/24/2006	TTN
257	723	2/24/2006	TTN
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMR
EAST		2/24/2006	TTN
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